Fig. 1 (a) Current versus time during oxidation performed under ramp voltage with \( V = -12 \) \( V \) for two exposure times (400ms and 1500 ms), \( T_d = T/2, R_e = R = V/T_d \). Solid lines represent the corresponding bias voltage waveform. (b) Differential conductance \( dI/dV \) plot of (a), (c) Height and volume of the oxide dots obtained with different exposure times, (d) AFM images of (c).
features in terms of volume and height. Under the same time integration parameter TI, ramp waveforms with high duty cycles produce more voluminous oxide dots while ramp waveforms with low duty cycles produce oxide dots with enhanced aspect ratio.

References